# TLP5832

### 1. Applications

- Industrial Inverters
- Air Conditioner Inverters
- Induction Cooktop and Home Appliances
- MOSFET Gate Drivers
- IGBT Gate Drivers

#### 2. General

The TLP5832 is a photocoupler in a 8-pin SO8L package that consists of a GaAlAs infrared light-emitting diode (LED) optically coupled to an integrated high-gain, high-speed photodetector IC chip. It provides guaranteed performance and specifications at temperature up to 110  $^{\circ}$ C.

The TLP5832 is physically smaller / thinner than the one in an 8-pin DIP package and compliant with international safety standards for reinforced insulation. It thus provides a smaller footprint solution for applications that require safety standard certification. An internal noise shield provides a guaranteed common-mode transient immunity of  $\pm 20$  kV/µs.

The TLP5832 is ideal for small to medium class IGBT and power MOSFET gate drive.

## 3. Features

- (1) Buffer logic type (totem pole output)
- (2) Output peak current: ±2.5 A (max)
- (3) Operating temperature: -40 to 110°C
- (4) Supply current: 3 mA (max)
- (5) Supply voltage: 15 to 30 V
- (6) Threshold input current: 5 mA (max)
- (7) Propagation delay time: 200 ns (max)
- (8) Common-mode transient immunity:  $\pm 20 \text{ kV/}\mu \text{s}$  (min)
- (9) Isolation voltage: 5000 Vrms (min)
- (10) Safety standards

UL-recognized: UL 1577, File No.E67349

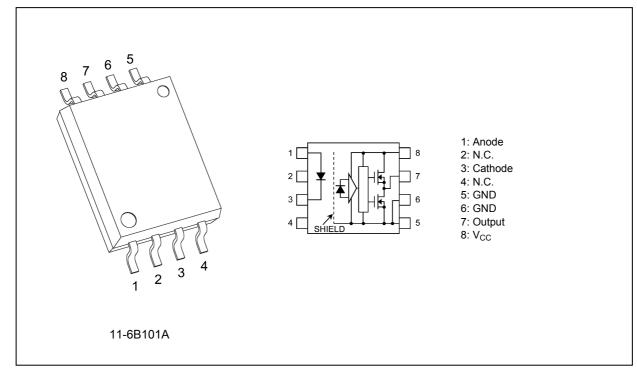
cUL-recognized: CSA Component Acceptance Service No.5A File No.E67349

VDE-approved: EN 60747-5-5, EN 62368-1 (Note 1)

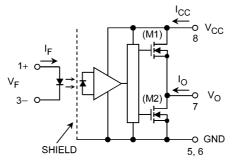
CQC-approved: GB4943.1, GB8898 Japan Factory (Pending)

Note 1: When a VDE approved type is needed, please designate the Option (D4).

## 4. Packaging and Pin Configuration



## 5. Internal Circuit (Note)



Note: A 1- $\mu F$  bypass capacitor must be connected between pin 8 and pin 5.

## 6. Principle of Operation

### 6.1. Truth Table

Input	LED	M1	M2	Output
Н	ON	ON	OFF	Н
L	OFF	OFF	ON	L

## 6.2. Mechanical Parameters

Characteristics	Size	Unit
Height	2.3 (max)	mm
Creepage distances	8.0 (min)	
Clearance distances	8.0 (min)	
Internal isolation thickness	0.4 (min)	

### 7. Absolute Maximum Ratings (Note) (Unless otherwise specified, $T_a = 25^{\circ}$ C)

	Characteristics		Symbol	Note	Rating	Unit
LED	Input forward current		١ <sub>F</sub>		20	mA
	Input forward current derating	$(T_a \ge 105 \ ^\circ C)$	$\Delta I_F / \Delta T_a$		-1	mA/°C
	Peak transient input forward current		I <sub>FPT</sub>	(Note 1)	1	A
	Peak transient input forward current derating	$(T_a \ge 85 \ ^\circ C)$	$\Delta I_{FPT} / \Delta T_a$		-25	mA/°C
	Input reverse voltage		V <sub>R</sub>		5	V
	Input power dissipation		PD		40	mW
	Input power dissipation derating	$(T_a \ge 85 \ ^\circ C)$	$\Delta P_D / \Delta T_a$		-1.0	mW/°C
Detector	Peak high-level output current	(T <sub>a</sub> = -40 to 110 °C)	I <sub>OPH</sub>	(Note 2)	-2.5	Α
	Peak low-level output current	(T <sub>a</sub> = -40 to 110 °C)	I <sub>OPL</sub>	(Note 2)	+2.5	
	Output voltage		Vo		35	V
	Supply voltage		V <sub>CC</sub>		35	
	Output power dissipation		Po		160	mW
	Output power dissipation derating	$(T_a \ge 85 \ ^\circ C)$	$\Delta P_0 / \Delta T_a$		-4.0	mW/°C
Common	Operating temperature		T <sub>opr</sub>		-40 to 110	°C
	Storage temperature		T <sub>stg</sub>		-55 to 125	
	Lead soldering temperature	(10 s)	T <sub>sol</sub>	(Note 3)	260	
	Isolation voltage	AC, 60 s, R.H. $\leq$ 60 %	BVS	(Note 4)	5000	Vrms

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

- Note 1: Pulse width (PW)  $\leq$  1  $\mu$ s, 300 pps
- Note 2: Exponential waveform. Pulse width  $\leq$  0.3  $\mu s,\,f\leq$  15 kHz
- Note 3:  $\geq$  2 mm below seating plane.
- Note 4: This device is considered as a two-terminal device: Pins 1, 2, 3 and 4 are shorted together, and pins 5, 6, 7 and 8 are shorted together.

#### 8. Recommended Operating Conditions (Note)

Characteristics	Symbol	Note	Min	Тур.	Max	Unit
Input on-state current	I <sub>F(ON)</sub>	(Note 1)	6.5	—	10	mA
Input off-state voltage	V <sub>F(OFF)</sub>		0	—	0.8	V
Supply voltage	V <sub>CC</sub>		15	—	30	
Peak high-level output current	I <sub>OPH</sub>	(Note 2)		—	-2.0	А
Peak low-level output current	I <sub>OPL</sub>	(Note 2)		—	+2.0	
Operating frequency	f	(Note 3)		—	50	kHz

Note: The recommended operating conditions are given as a design guide necessary to obtain the intended performance of the device. Each parameter is an independent value. When creating a system design using this device, the electrical characteristics specified in this datasheet should also be considered.

Note: A ceramic capacitor (1  $\mu$ F) should be connected between pin 8 (V<sub>CC</sub>) and pin 5 (GND) to stabilize the operation of a high-gain linear amplifier. Otherwise, this photocoupler may not switch properly. The bypass capacitor should be placed within 1 cm of each pin.

- Note 1: The rise and fall times of the input on-current should be less than 0.5  $\mu s.$
- Note 2: Exponential waveform. I\_{OPH}  $\geq$  -2.0 A ( $\leq$  0.3  $\mu s$ ), I\_{OPL}  $\leq$  2.0 A ( $\leq$  0.3  $\mu s$ ), VCC = 15 V, T\_a = 110 °C
- Note 3: Denotes the operating range, not the recommended operating condition.

### 9. Electrical Characteristics (Note) (Unless otherwise specified, T<sub>a</sub> = -40 to 110°C)

Characteristics	Symbol	Note	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Input forward voltage	V <sub>F</sub>			I <sub>F</sub> = 10 mA, T <sub>a</sub> = 25 °C	1.45	1.55	1.70	V
Input forward voltage temperature coefficient	$\Delta V_F / \Delta T_a$			I <sub>F</sub> = 10 mA	—	-2.0	_	mV/°C
Input reverse current	I <sub>R</sub>			V <sub>R</sub> = 5 V, T <sub>a</sub> = 25 °C	_	—	10	μA
Input capacitance	Ct			V = 0 V, f = 1 MHz, T <sub>a</sub> = 25 °C	_	60	_	pF
Peak high-level output current	I <sub>OPH</sub>	(Note 1)	Fig. 12.1.1	I <sub>F</sub> = 5 mA, V <sub>CC</sub> = 15 V, V <sub>8-7</sub> = -3.5 V	—	-1.6	-1.0	A
				I <sub>F</sub> = 5 mA, V <sub>CC</sub> = 15 V, V <sub>8-7</sub> = -7 V	—	—	-2.0	
Peak low-level output current	I <sub>OPL</sub>	(Note 1)	Fig. 12.1.2	I <sub>F</sub> = 0 mA, V <sub>CC</sub> = 15 V, V <sub>7-5</sub> = 2.5 V	1.0	1.6	—	
				I <sub>F</sub> = 0 mA, V <sub>CC</sub> = 15 V, V <sub>7-5</sub> = 7 V	2.0	—	_	
High-level output voltage	V <sub>OH</sub>		Fig. 12.1.3	$I_F$ = 5 mA, R <sub>L</sub> = 200 Ω, V <sub>CC1</sub> = +15 V, V <sub>EE1</sub> = -15 V	11.0	13.7		V
Low-level output voltage	V <sub>OL</sub>		Fig. 12.1.4	$V_{F} = 0.8 V, R_{L} = 200 \Omega,$ $V_{CC1} = +15 V, V_{EE1} = -15 V$	—	-14.9	-12.5	
High-level supply current	I <sub>ССН</sub>		Fig. 12.1.5	$I_F$ = 10 mA, $V_{CC}$ = 30 V, $V_O$ = Open	—	1.5	3.0	mA
Low-level supply current	I <sub>CCL</sub>		Fig. 12.1.6	$I_F = 0 \text{ mA}, V_{CC} = 30 \text{ V},$ $V_O = \text{Open}$	—	1.5	3.0	
Threshold input current (L/H)	I <sub>FLH</sub>			V <sub>CC</sub> = 15 V, V <sub>O</sub> > 1 V	_	1.0	5.0	
Threshold input voltage (H/L)	V <sub>FHL</sub>			V <sub>CC</sub> = 15 V, V <sub>O</sub> < 1 V	0.8		_	V
Supply voltage	V <sub>CC</sub>				15		30	
UVLO threshold voltage	V <sub>UVLO+</sub>			I <sub>F</sub> = 5 mA, V <sub>O</sub> > 2.5 V	11.0	12.5	13.5	
	V <sub>UVLO-</sub>			I <sub>F</sub> = 5 mA, V <sub>O</sub> < 2.5 V	9.5	11.0	12.0	
UVLO hysteresis	UVLO <sub>HYS</sub>			—	_	1.5	_	

Note: All typical values are at  $T_a = 25$  °C.

Note: This device is designed for low power consumption, making it more sensitive to ESD than its predecessors. Extra care should be taken in the design of circuitry and pc board implementation to avoid ESD problems.

Note 1:  $I_O$  application time  $\leq$  50  $\mu s;$  single pulse.

### 10. Isolation Characteristics (Unless otherwise specified, $T_a = 25^{\circ}C$ )

Characteristics	Symbol	Note	Test Conditions	Min	Тур.	Max	Unit
Total capacitance (input to output)	Cs	(Note 1)	V <sub>S</sub> = 0 V, f = 1 MHz	—	1.0	—	pF
Isolation resistance	R <sub>S</sub>	(Note 1)	V <sub>S</sub> = 500 V, R.H. ≤ 60 %	1 × 10 <sup>12</sup>	1014	_	Ω
Isolation voltage	BVS	(Note 1)	AC, 60 s	5000	_	_	Vrms

Note 1: This device is considered as a two-terminal device: Pins 1, 2, 3 and 4 are shorted together, and pins 5, 6, 7 and 8 are shorted together.

## 11. Switching Characteristics (Note) (Unless otherwise specified, $T_a = -40$ to 110°C)

Characteristics	Symbol	Note	Test Circuit	Test Condition	Min	Тур.	Max	Unit
Propagation delay time (L/H)	t <sub>pLH</sub>	(Note 1)	Fig. 12.1.7	$    I_F = 0 \rightarrow 5 \text{ mA}, V_{CC} = 30 \text{ V}, \\ R_g = 20 \Omega, C_g = 10 \text{ nF} $	50	_	200	ns
Propagation delay time (H/L)	t <sub>pHL</sub>			$    I_F = 5 \rightarrow 0 \text{ mA, } V_{CC} = 30 \text{ V,} \\ R_g = 20 \Omega, C_g = 10 \text{ nF} $	50		200	
Rise time	t <sub>r</sub>	(Note 1)	o	$    I_F = 0 \rightarrow 5 \text{ mA, } V_{CC} = 30 \text{ V,} \\ R_g = 20 \Omega, C_g = 10 \text{ nF} $	—	15	—	
Fall time	t <sub>f</sub>	(Note 1)		$    I_F = 5 \rightarrow 0 \text{ mA, } V_{CC} = 30 \text{ V,} \\ R_g = 20 \Omega, C_g = 10 \text{ nF} $	—	8	—	
Pulse width distortion	t <sub>pHL</sub> -t <sub>pLH</sub>	(Note 1)		$I_F = 0 \leftrightarrow 5 \text{ mA}, V_{CC} = 30 \text{ V},$	_	_	50	
Propagation delay skew (device to device)	t <sub>psk</sub>	(Note 1), (Note 2)		R <sub>g</sub> = 20 Ω, C <sub>g</sub> = 10 nF	-80		80	
High-level common-mode transient immunity	CM <sub>H</sub>	(Note 3)	Fig. 12.1.8	$V_{CM} = 1000 V_{p-p}, I_F = 5 mA, V_{CC} = 30 V, T_a = 25 °C, V_{O(min)} = 26 V$	±20	±25	—	kV/μs
Low-level common-mode transient immunity	CML	(Note 4)		$V_{CM} = 1000 V_{p-p}, I_F = 0 mA, V_{CC} = 30 V, T_a = 25 °C, V_{O(max)} = 1 V$	±20	±25	_	

Note: All typical values are at  $T_a = 25$  °C.

Note 1: Input signal (f = 25 kHz, duty = 50 %,  $t_r = t_f = 5$  ns or less).

C<sub>L</sub> is approximately 15 pF which includes probe and stray wiring capacitance.

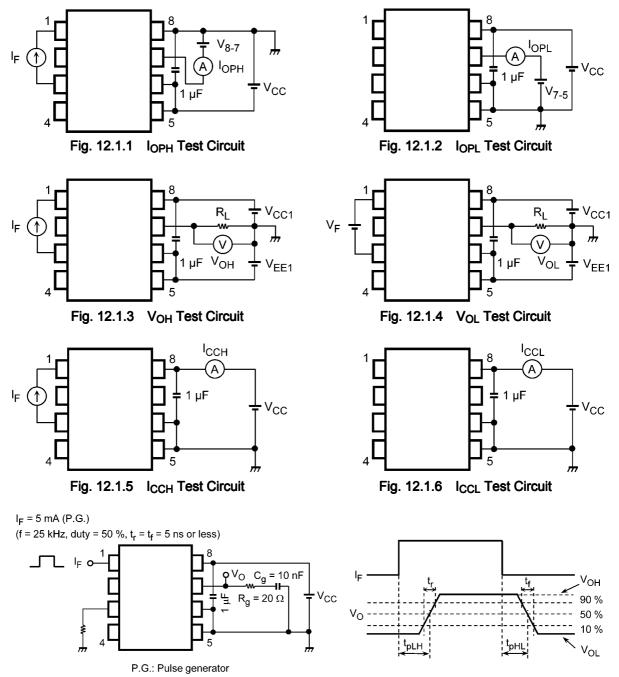
Note 2: The propagation delay skew, t<sub>psk</sub>, is equal to the magnitude of the worst-case difference in t<sub>pHL</sub> and/or t<sub>pLH</sub> that will be seen between units at the same given conditions (supply voltage, input current, temperature, etc).

Note 3:  $CM_H$  is the maximum rate of fall of the common mode voltage that can be sustained with the output voltage in the logic high state (V<sub>O</sub> > 26 V).

Note 4:  $CM_L$  is the maximum rate of rise of the common mode voltage that can be sustained with the output voltage in the logic low state (V<sub>O</sub> < 1 V).

12. Test Circuits and Characteristics Curves

## 12.1. Test Circuits







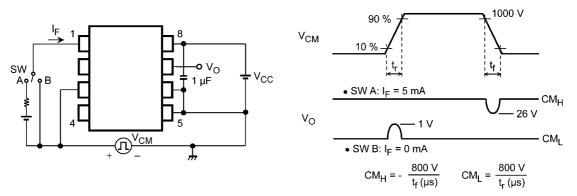
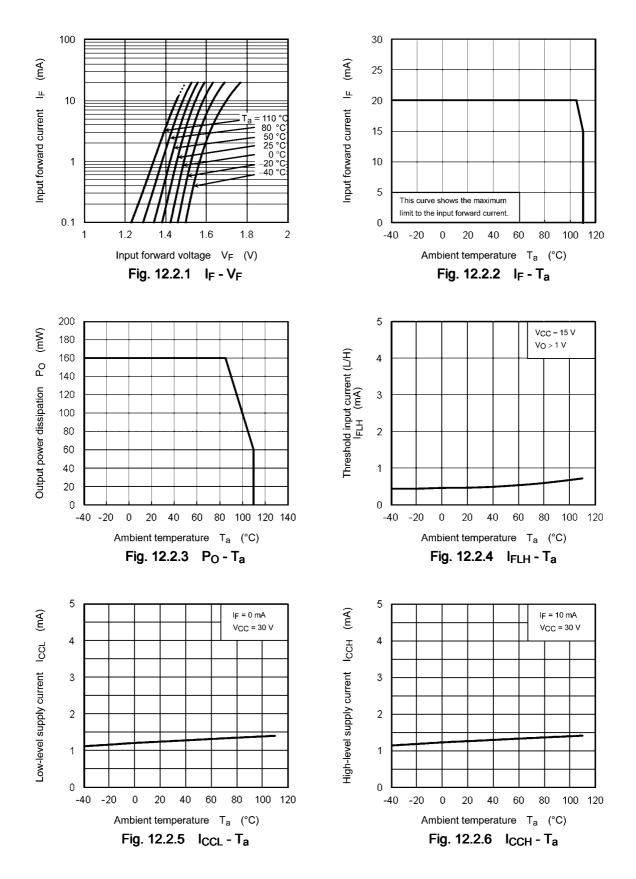
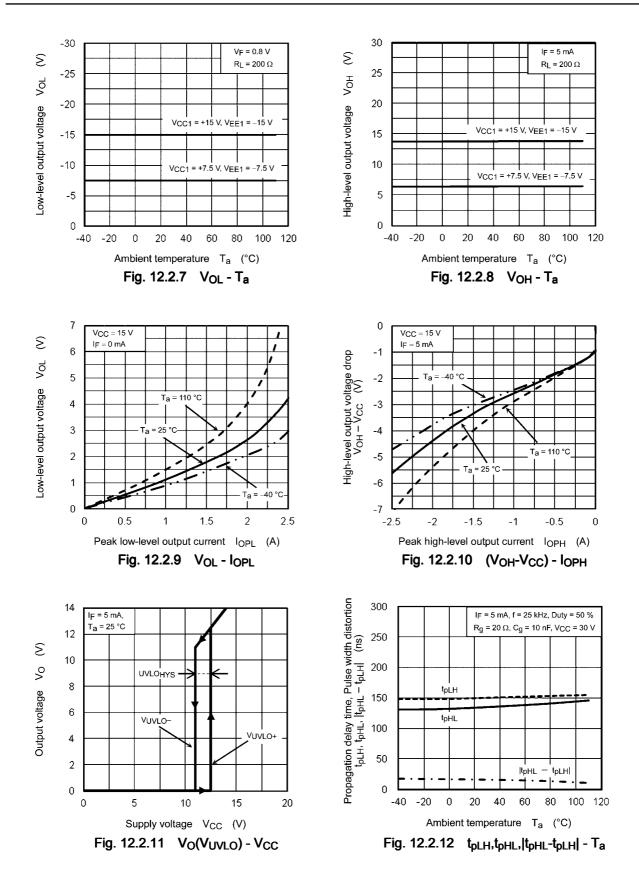
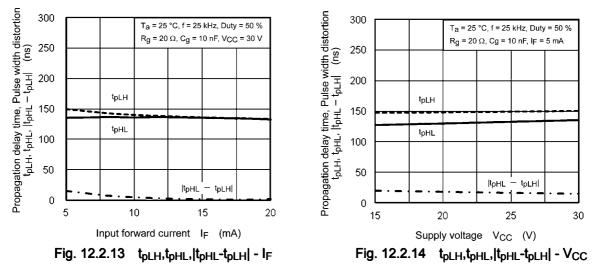


Fig. 12.1.8 Common-Mode Transient Immunity and Waveform

## 12.2. Characteristics Curves (Note)







Note: The above characteristics curves are presented for reference only and not guaranteed by production test, unless otherwise noted.

## 13. Soldering and Storage

#### 13.1. Precautions for Soldering

The soldering temperature should be controlled as closely as possible to the conditions shown below, irrespective of whether a soldering iron or a reflow soldering method is used.

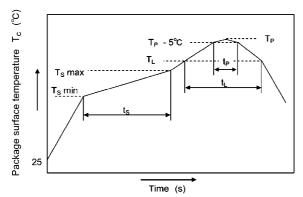
• When using soldering reflow.

The soldering temperature profile is based on the package surface temperature.

(See the figure shown below, which is based on the package surface temperature.)

Reflow soldering must be performed once or twice.

The mounting should be completed with the interval from the first to the last mountings being 2 weeks.



	Symbol	Min	Max	Unit
Preheat temperature	Ts	150	200	°C
Preheat time	ts	60	120	s
Ramp-up rate ( $T_L$ to $T_P$ )			3	°C/s
Liquidus temperature	TL	217		°C
Time above $T_L$	tL	60	150	S
Peak temperature	Τ <sub>Ρ</sub>		260	°C
Time during which $T_c$ is between (T <sub>P</sub> – 5) and T <sub>P</sub>	t₽		30	S
Ramp-down rate $(T_P \text{ to } T_L)$			6	°C/s

Fig. 13.1.1 An example of a temperature profile when lead(Pb)-free solder is used

When using soldering flow

Preheat the device at a temperature of 150  $^{\circ}$ C (package surface temperature) for 60 to 120 seconds. Mounting condition of 260  $^{\circ}$ C within 10 seconds is recommended.

Flow soldering must be performed once.

When using soldering Iron

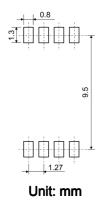
Complete soldering within 10 seconds for lead temperature not exceeding 260 °C or within 3 seconds not exceeding 350 °C

Heating by soldering iron must be done only once per lead.

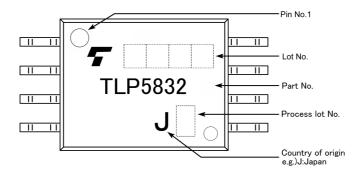
### 13.2. Precautions for General Storage

- Avoid storage locations where devices may be exposed to moisture or direct sunlight.
- Follow the precautions printed on the packing label of the device for transportation and storage.
- Keep the storage location temperature and humidity within a range of 5 °C to 35 °C and 45 % to 75 %, respectively.
- Do not store the products in locations with poisonous gases (especially corrosive gases) or in dusty conditions.
- Store the products in locations with minimal temperature fluctuations. Rapid temperature changes during storage can cause condensation, resulting in lead oxidation or corrosion, which will deteriorate the solderability of the leads.
- When restoring devices after removal from their packing, use anti-static containers.
- Do not allow loads to be applied directly to devices while they are in storage.
- If devices have been stored for more than two years under normal storage conditions, it is recommended that you check the leads for ease of soldering prior to use.

## 14. Land Pattern Dimensions for Reference Only



## 15. Marking



## 16. EN 60747-5-5 Option (D4) Specification

- Part number: TLP5832 (Note 1)
- The following part naming conventions are used for the devices that have been qualified according to option (D4) of EN 60747.

Example: TLP5832(D4-TP,E

D4: EN 60747 option TP: Tape type E: [[G]]/RoHS COMPATIBLE **(Note 2)** 

Note 1: Use TOSHIBA standard type number for safety standard application.

e.g., TLP5832(D4-TP,E  $\rightarrow$  TLP5832

Note 2: Please contact your Toshiba sales representative for details on environmental information such as the product's RoHS compatibility.

RoHS is the Directive 2011/65/EU of the European Parliament and of the Council of 8 June 2011 on the restriction of the use of certain hazardous substances in electrical and electronic equipment.

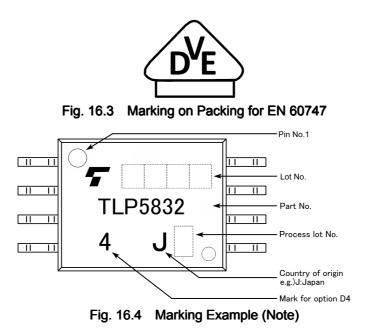
Description	Symbol	Rating	Unit
Application classification			
for rated mains voltage $\leq$ 600 Vrms for rated mains voltage $\leq$ 1000 Vrms		I-IV I-III	_
Climatic classification		40 / 110 / 21	_
Pollution degree		2	_
Maximum operating insulation voltage	VIORM	1230	Vpeak
Input to output test voltage, Method A Vpr = 1.6 × VIORM, type and sample test tp = 10 s, partial discharge < 5 pC	Vpr	1970	Vpeak
Input to output test voltage, Method B Vpr = 1.875 × VIORM, 100 % production test tp = 1 s, partial discharge < 5 pC	Vpr	2310	Vpeak
Highest permissible overvoltage (transient overvoltage, t <sub>pr</sub> = 60 s)	VTR	8000	Vpeak
Safety limiting values (max. permissible ratings in case of fault, also refer to thermal derating curve) current (input current IF, P <sub>so</sub> = 0) power (output or total power dissipation) temperature	lsi Pso Ts	300 700 150	mA mW °C
Insulation resistance $V_{IO} = 500 \text{ V}, \text{ T}_{a} = 25 ^{\circ}\text{C}$ $V_{IO} = 500 \text{ V}, \text{ T}_{a} = 100 ^{\circ}\text{C}$ $V_{IO} = 500 \text{ V}, \text{ T}_{a} = \text{T}_{s}$	Rsi	$\ge 10^{12}$ $\ge 10^{11}$ $\ge 10^{9}$	Ω

Fig. 16.1 EN 60747 Insulation Characteristics

Minimum creepage distance	Cr	8.0 mm
Minimum clearance	CI	8.0 mm
Minimum insulation thickness	ti	0.4 mm
Comparative tracking index	CTI	175

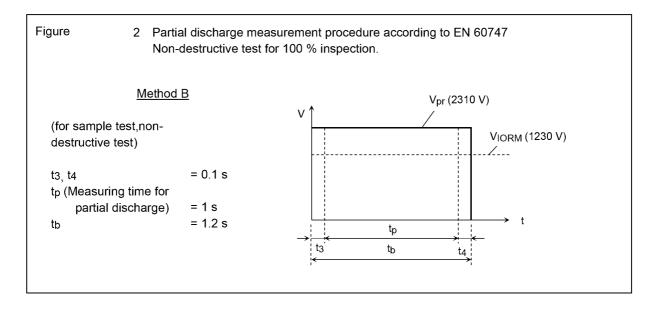
Fig. 16.2 Ins	sulation Related	Specifications	(Note)
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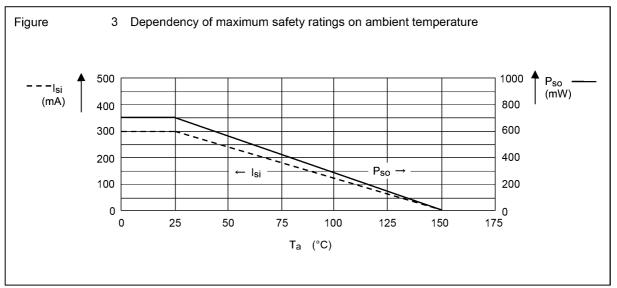
Note: This photocoupler is suitable for safe electrical isolation only within the safety limit data. Maintenance of the safety data shall be ensured by means of protective circuits.



Note: The above marking is applied to the photocouplers that have been qualified according to option (D4) of EN 60747.

		asurement procedure according to EN 60747 ualification and sampling tests.
Me	thod A	VINITIAL (8 KV)
(for type and samp destructive tests)	ing tests,	V Vpr (1970 V)
t1, t2	= 1 to 10 s	VIORM (1230 V)
t3, t4	= 1 s	
tp (Measuring time	for	
partial discharg	je) = 10 s	$0 \xrightarrow{l} t \xrightarrow{l} t$
tb	= 12 s	$t_3$ $t_p$ $t_4$
tini	= 60 s	tı tini tızı tı







## 17. Embossed-Tape Packing (TP) Specification for Mini-Flat Photocouplers

### 17.1. Applicable Package

Package Name	Product Type
SO8L	Long creepage mini flat coupler

#### 17.2. Product Naming Conventions

Type of package used for shipment is denoted by a symbol suffix after a part number. The method of classification is as below.

Example) TLP5832(TP,E

Part number: TLP5832 Tape type: TP [[G]]/RoHS COMPATIBLE: E **(Note 1)** 

Note: Please contact your Toshiba sales representative for details on environmental information such as the product's RoHS compatibility.

RoHS is the Directive 2011/65/EU of the European Parliament and of the Council of 8 June 2011 on the restriction of the use of certain hazardous substances in electrical and electronic equipment.

#### 17.3. Tape Dimensions Specification

Таре Туре	Division	Packing Amount (A unit per reel)
TP	—	1500

### 17.3.1. Orientation of Device in Relation to Direction of Feed

Device orientation in the carrier cavities as shown in Fig. 17.3.1.1.

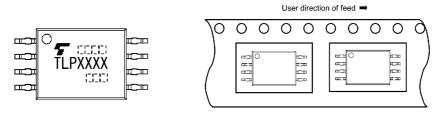


Fig. 17.3.1.1 Device Orientation

### 17.3.2. Empty Cavities

Characteristics	Criterion	Remarks
Occurrences of 2 or more successive empty cavities	0 device	Within any given 40-mm section of tape, not including leader and trailer
Single empty cavity	6 devices (max) per reel	Not including leader and trailer

### 17.3.3. Tape Leader and Trailer

The start of the tape has 14 or more empty holes. The end of the tape has 34 or more empty holes and more than 30mm only for a cover tape.

### 17.3.4. Tape Dimensions

Tape material: Plastic (for protection against static electricity)

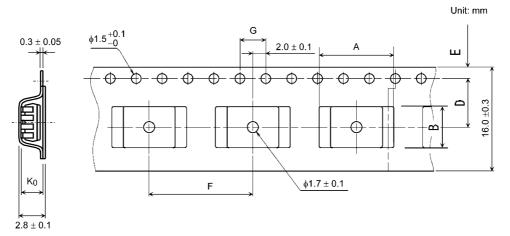


Table	<b>Tape Dimensions</b>	(unit: mm	tolerance: +0.1)
labic			, where $a \to 0.1$

Symbol	Dimension	Remark
A	10.4	_
В	6.35	_
D	7.5	Center line of embossed cavity and sprocket hole
E	1.75	Distance between tape edge and sprocket hole center
F	12.0	Cumulative error +0.1/-0.3 per 10 empty cavities holes
G	4.0	Cumulative error +0.1/-0.3 per 10 sprocket holes
K <sub>0</sub>	2.4	Internal space

### 17.3.5. Reel Specification

Material: Plastic (for protection against static electricity)

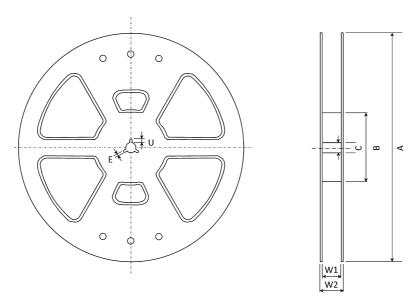


Table Reel Dimensions (unit: mm)

Symbol	Dimension
А	$\phi 330\pm 2$
В	$\varphi 100 \pm 1$
С	$\phi 13 \pm 0.5$
E	$2.0\pm0.5$
U	$4.0\pm0.5$
W1	17.4 ± 1.0
W2	21.4 ± 1.0

### 17.4. Packing (Note)

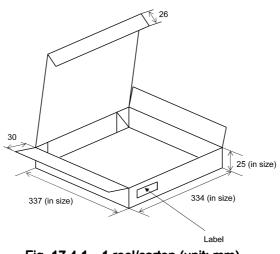


Fig. 17.4.1 1 reel/carton (unit: mm)

Note: Taping reel diameter: \$330 mm

#### 17.5. Label Format

(1) Carton: The label provides the part number, quantity, lot number, the Toshiba logo, etc.

(2) Reel: The label provides the part number, the taping name, quantity, lot number, etc.

## 17.6. Ordering Information

When placing an order, please specify the part number, tape type and quantity as shown in the following example.

Example) TLP5832(TP,E 1500 pcs

Part number: TLP5832 Tape type: TP (12-mm pitch) [[G]]/RoHS COMPATIBLE: E **(Note 1)** Quantity (must be a multiple of 1500): 1500 pcs

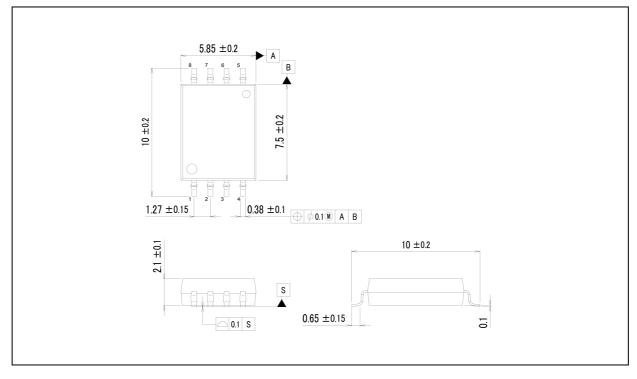
Note : Please contact your Toshiba sales representative for details on environmental information such as the product's RoHS compatibility. RoHS is the Directive 2011/65/EU of the European Parliament and of the Council of 8 June 2011 on the

RoHS is the Directive 2011/65/EU of the European Parliament and of the Council of 8 June 2011 on the restriction of the use of certain hazardous substances in electrical and electronic equipment.

## TLP5832

## Package Dimensions

Unit: mm



Weight: 0.203 g (typ.)

	Package Name(s)
TOSHIBA: 11-6B101A	

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